## Bending the performance limits of X-ray crystal spectrometers

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High accuracy of the measurement equipment is essential for the successful experiment. The state-of-the-art research requires constantly improving measurement devices, which forces experimentalists to think new creative ways to enhance their precision on the edge of their physical limitations. In this poster I will present methods that have been recently developed in collaboration with the European Synchrotron Radiation Facility (Grenoble, France) to increase the energy and spatial resolutions of Johann type X-ray spectrometer without any extra cost.